PCN Number: 20150317004 PCN Date: 04/17/2015									7/2015										
Title	Title: DLPA3000 & DLPA3005 A3 Redesign																		
Cus	tome	er C	onta	ct:	Dlp	pcn_tea	m@l	ist.ti	i.com		Dept:			DLF	P®	CQE			
Proposed 1st Ship Date: 10/01					/20	/2015 Estimated Avai				Sample June 1				, 201	.5				
Cha	Change Type:																		
			y Site					□ Design □					Wafer Bump Site						
	Assembly Process				Data Sheet								afer Bump Material						
Assembly Materials				Щ	Part number char					Щ			fer Bump Process						
	Mechanical Specification				닏	Test Site				\blacksquare	Wafer Fab Site Wafer Fab Materials								
Packing/Shipping/Labeling					Test Process				_										
									3										
_	PCN Details																		
	Description of Change:																		
	Texas Instruments Incorporated is announcing initial notification for qualification of the																		
DLF	DLPA3000 & DLPA3005 A3 Re-design.																		
*Firs	*First Ship Date is based on the scheduled Qualification plan completion date. The First Ship																		
	Date will be updated on the Final PCN based on the actual Qualification plan completion date.																		
Reason for Change:																			
Design Enhancements																			
-Low Vin to allow 6VIN , supports dual battery implementations.																			
	-High Vin to allow +20VIN FOR PAD 3000																		
	- Activate all 3GP ANC Bucks																		
	Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):																		
	Additional Functions - See Reasons for Change section directly above.																		
	Changes to product identification resulting from this PCN:																		
	The part will be marked with revision D instead of revision C.																		
Exar	Example:																		
_	Current Marking DLPA3000 C will become DLPA3000 D																		
Product Affected:																			
DLPA3000CPFD, DLPA3000CPFDR, DLPA3005CPFD, DLPA3005CPFDR, PAD3000A2PFD, DAD3006A3PFDR, DAD3006A3PFDR																			
PAD3000A2PFDR, PAD3005A2PFD, PAD3005A2PFDR																			
Qualification Plan																			
Qualification Plan This qualification has been developed for the validation of this change. The qualification data																			
validates that the proposed change meets the applicable released technical specifications.																			
			n Sch				tart		May 2			cu		End		•		15, 2	
Quu		10.0	<u> </u>	icaa			tai t	•	riuy Z	,	2015			LIIG		Ju	110	15, 2	2013
	Qual Vehicle: Device Vehicle (DLPA3000D & DLPA3005D)																		
	Ovelification. M Disc. Toot Beauty																		
Qualification:																			

Qualification Plan

Test	Conditions	Read Points	Sample Size
A. Life Test:			
High Temperature Operating Life	140C	480 hours	QBS(1)
B. Environmental Tests:			
Preconditioning + Temperature Cycling:			
(a) Preconditioning	MSL2; 85C/60%RH	168hrs	QBS(1)
(b) Temperature Cycling	-65C/+150C	500 cycles	
ESD	НВМ	+/- 2000V	QBS(1)
ESD	CDM	+/- 750V	QBS(1)
Electrical Characterization	Per data sheet		30 (each)
Latch Up	70C	+/- 100mA	QBS(1)
C. Inspection Tests:			
X-Ray	Top view only		QBS(1)
D. Other			
Manufacturing Qual	TITL ERTP		1 lot (each)

Notes:

1) QBS (Qual by Similarity) to DLPA3000C

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
DLP PCN Team	dlp pcn team@ti.com
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com